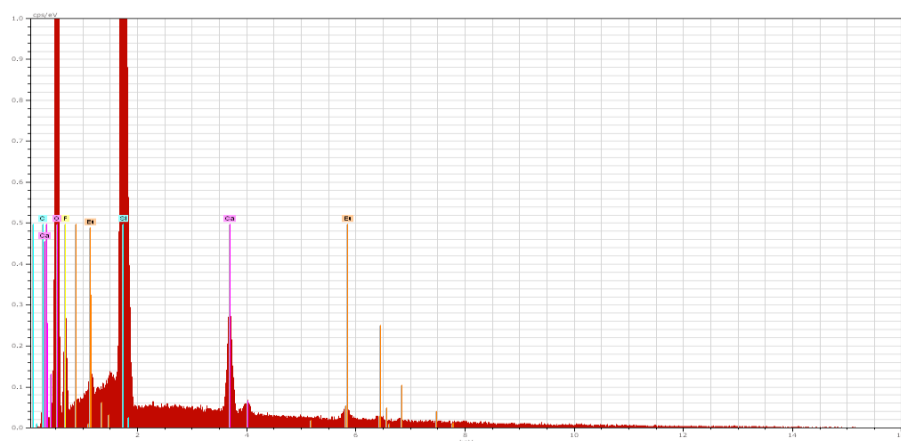


Application Note



Spectrum: spectrum

El	AN	Series	unn. C [wt.-%]	norm. C [wt.-%]	Atom. C [at.-%]	Error [%]
C	6	K-series	1.34	1.13	1.93	0.3
O	8	K-series	47.89	40.49	51.84	5.5
F	9	K-series	18.21	15.39	16.60	2.9
Si	14	K-series	45.25	38.26	27.91	1.9
Ca	20	K-series	3.41	2.88	1.47	0.1
Eu	63	L-series	2.19	1.85	0.25	0.1
Total:			118.29	100.00	100.00	

Figure S1. The EDX spectra analysis of the glass-ceramic sample.

The XPS spectra recorded on SiO₂-CaF₂-Eu glass-ceramic sample annealed in reducing atmosphere, shown in different energy regions

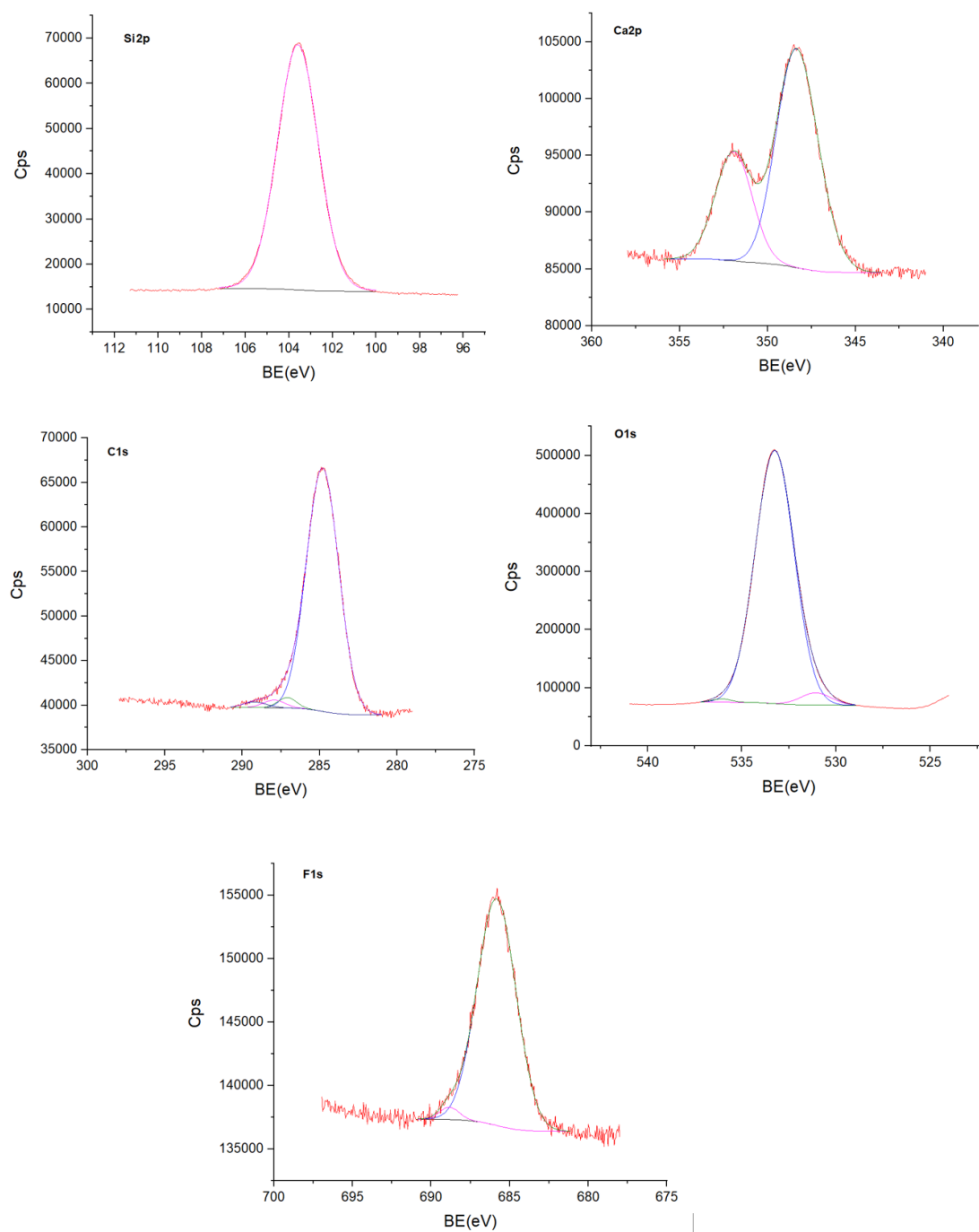


Figure S2. The XPS spectra were recorded on the glass-ceramic sample annealed in reducing atmosphere and shown in different energy regions.